



Optics and Spectroscopy for Fluid Characterization

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Message from the Guest Editor

Dear Colleagues,

All over the world, there is a huge and ever-increasing interest in the development and application of optical and spectroscopic techniques to characterize fluids in engineering and science. Methods in this category have substantially advanced our understanding of fluids (gases, liquids, and multiphase). This is particularly true for the last 50 years, as laser-based techniques became gold standards in the analytical sciences and engineering. A key feature of such light-based methods is that they are usually non-intrusive and hence they do not notably alter the systems under investigation. The list of parameters and characteristics that can be measured by optical and spectroscopic techniques in a fluid is long. The list of techniques is long as well. The Special Issue will focus on recent developments in optical and spectroscopic techniques for fluid characterization. It will show the breadth of the field including advances in hardware and instrumentation, methodology, and practical implementation.





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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal *Applied Sciences* has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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